Introduction

VLSI CAD

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Course Objective

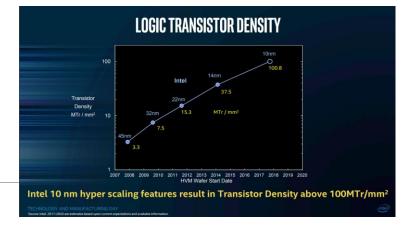
- To get an idea about chip design concepts
- •To get an idea about chip design problems that CAD tools help to solve
- To get an idea about emerging design and CAD challenges
- •To get an idea about algorithms and data structures used in VLSI CAD tools

Course outline

- 1. Introduction
- 2. Basic algorithms on graphs
- 3. Static timing analysis
- 4. Routing
- 5. Placement
- 6. Buffer insertion
- 7. Computational Boolean algebra
- 8. BDDs
- 9. Two-level logic synthesis
- 10. Multi-level logic synthesis
- **11**. SAT
- 12. Technology mapping

Trends in microelectronics

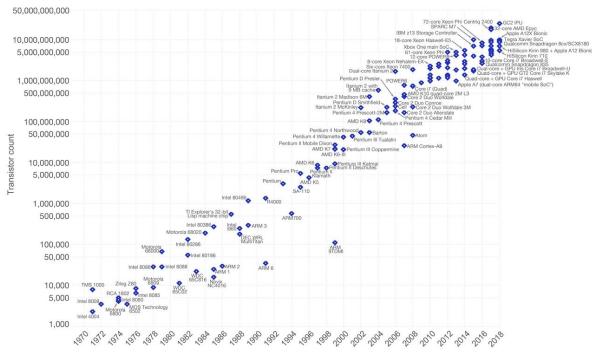
- Improvements in device technology
 - Smaller circuits
 - Higher performance
 - More devices on a chip
- Higher degree of integration
 - More complex systems
 - Higher reliability challenges
 - Lower cost of computation
- Design considerations:
 - Use most recent technologies: to be competitive in performance
 - Reduce design cost: to be competitive in price
 - Time-to-market is critical: speedup design time



Moore's Law – The number of transistors on integrated circuit chips (1971-2018)

Our World in Data

Moore's law describes the empirical regularity that the number of transistors on integrated circuits doubles approximately every two years. This advancement is important as other aspects of technological progress – such as processing speed or the price of electronic products – are linked to Moore's law.



Data source: Wikipedia (https://en.wikipedia.org/wiki/Transistor_count)
The data visualization is available at OurWorldinData.org. There you find more visualizations and research on this topic

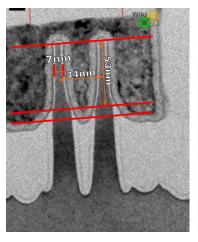
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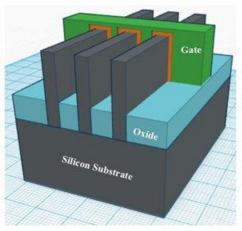
Feature size scaling. Intel history

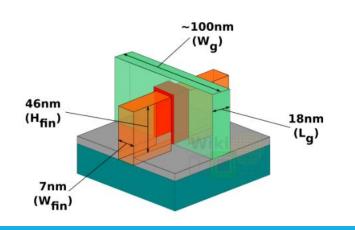
- There is physical limit to minimal printable critical dimension: $CD = k_1 \frac{\lambda}{NA}$. This imposes complex challenges for photolithography for nodes beyond 90nm
- Small devices also have physical problems: switching speed, leakage power, etc.
- Thin wires suffer from high resistivity and electromigration
- Over years, the layout has become more regular, and lot of materials research has been done to keep Moor's law alive

| 2003 | 90nm | Strained Si |
|------|------|----------------------------------|
| 2005 | 65nm | |
| 2007 | 45nm | High-k and Metal Gate Transistor |
| 2009 | 32nm | Wet lithography |
| 2011 | 22nm | FinFET transistors |
| 2014 | 14nm | Non-copper critical metal layers |
| 2019 | 10nm | |
| 2021 | 7nm | EUV |

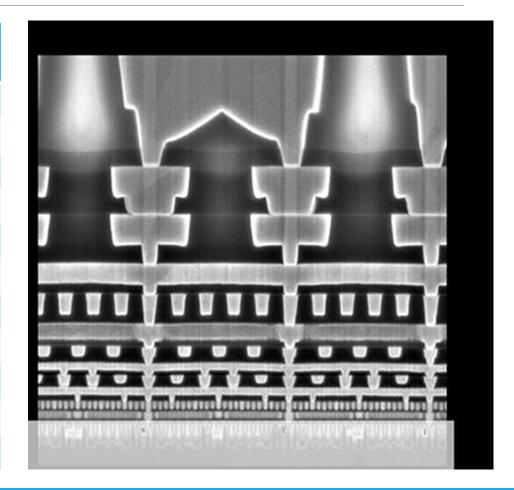
Intel's 10 nm process technology







| Feature | Pitch, |
|---------|--------|
| | nm |
| Fin | 34 |
| Gate | 54 |
| MO | 40 |
| M1 | 36 |
| M2-M4 | 44 |
| M5 | 52 |
| M6 | 84 |
| M7-M8 | 112 |
| M9-M10 | 160 |
| TM0 | 1080 |
| TM1 | 11K |

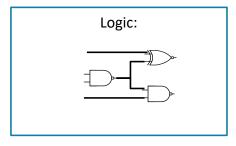


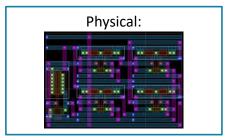
Microelectronics design problems

- •Intrinsic physical scaling limits
- Capital investment for fabrication
- Large-scale design management: use CAD design tools

Modeling abstractions

Architectural: ... PC = PC+1; FETCH (PC) DECODE(INSTR) ...

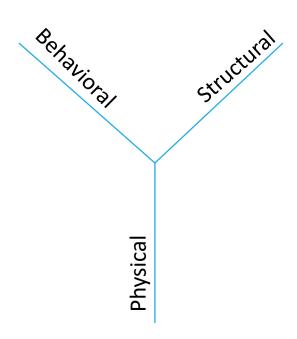




- Architectural level:
 - Operations implemented by resources

- Logic level:
 - Logic functions implemented by gates
- Physical level:
 - Physics of devices modeled
 - Devices are geometrical objects

Modeling views



- Behavioral view:
 - Abstract function
- Structural view:
 - Interconnection of parts
- Physical view:
 - Physical objects with sizes and positions

Circuit optimization

- Performance
 - Delay and cycle time
 - Latency
 - Throughput
- Power consumption
- •Area (yield and packaging cost)
- Manufacturing (yield)
- Testability

VLSI CAD

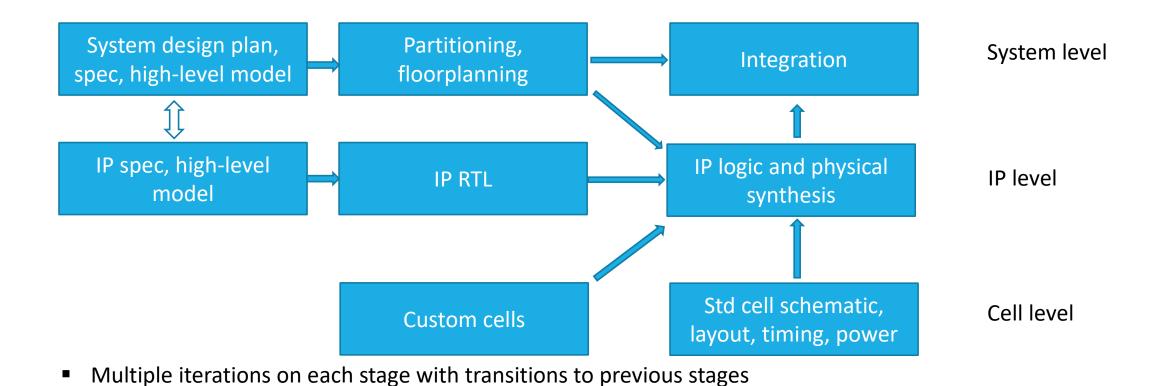
- CAD (Computer-Aided Design) tools: software that help designer in design process (wide design types)
- •EDA (Electronic Design Automation): software tools for designing electronic systems, e.g. integrated circuits)
- •The tools work together in a design flow that designers use to make the design
- •Can be seen as a compiler from algorithm to mask patterns

Designer roles

- Architects develop specifications
- •Microarchitects define functional blocks
- Logic designers write detailed description of functional blocks (RTL)
- •Circuit designers implement logic in transistors
- •Mask designers draw layers to create transistors
- •Integration team assembles components to a product
- Validation Engineers check for errors at every step
- Design Automation provides CAD tool support at every step

Generalized design flow

Continuous validation (performance and functional)

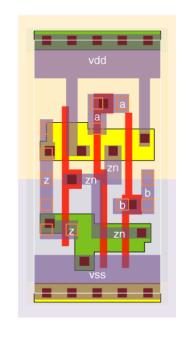


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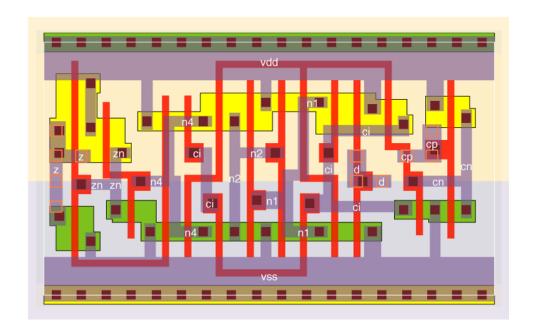
Standard Cell Library

- Standard cell libraries contain models for basic building blocks for digital design
- Library build process is called characterization. Includes comprehensive SPICE simulations, manual or automated schematic/layout creation
- Different CAD tools use different cell models (or views)
 - Logical view for logic synthesis
 - Physical layout view for physical synthesis
 - Timing, power, noise, parasitics for performance validation

Cell layout examples



and2 layout



flipflop layout

Cell timing example

```
cell (INVX1) {
 cell footprint : inv;
  area : 129.6;
 cell_leakage_power : 0.0310651;
 pin(A) {
    direction : input;
    capacitance : 0.0159685;
    rise_capacitance : 0.0159573;
    fall_capacitance : 0.0159685; }
  pin(Y) {
    direction : output;
    capacitance : 0;
    rise_capacitance : 0;
    fall_capacitance : 0;
    max_capacitance : 0.394734;
    function : "(!A)";
    timing() {
      related pin : "A";
      timing_sense : negative_unate;
      cell_rise(delay_template_5x5) (
       index_1 ("0.06, 0.18, 0.42, 0.6, 1.2");
        index_2 ("0.025, 0.05, 0.1, 0.3, 0.6");
        values ( \
          "0.147955, 0.218038, 0.359898, 0.922746, 1.76604", \
          "0.224384, 0.292903, 0.430394, 0.991288, 1.83116",
          "0.365378, 0.448722, 0.584275, 1.13597, 1.97017", \
          "0.462096, 0.551586, 0.70164, 1.24437, 2.08131", \
          "0.756459, 0.874246, 1.05713, 1.62898, 2.44989"); }
```

```
rise_transition(delay_template_5x5) (
    index_1 ("0.06, 0.18, 0.42, 0.6, 1.2");
   index_2 ("0.025, 0.05, 0.1, 0.3, 0.6");
    values ( ... ); )
  cell_fall(delay_template_5x5) {
    index_1 ("0.06, 0.18, 0.42, 0.6, 1.2");
   index_2 ("0.025, 0.05, 0.1, 0.3, 0.6");
    values ( ... ); }
  fall_transition(delay_template_5x5) {
    index_1 ("0.06, 0.18, 0.42, 0.6, 1.2");
   index_2 ("0.025, 0.05, 0.1, 0.3, 0.6");
   values ( ... ); )
} /* end timing */
internal_power()
  related pin : "A";
  rise_power(energy_template_5x5)
    index_1 ("0.06, 0.18, 0.42, 0.6, 1.2");
   index_2 ("0.025, 0.05, 0.1, 0.3, 0.6");
    values ( ... ); }
  fall_power(energy_template_5x5) {
    index_1 ("0.06, 0.18, 0.42, 0.6, 1.2");
    index_2 ("0.025, 0.05, 0.1, 0.3, 0.6");
   values ( ... ); }
} /* end internal power */
/* end Pin Y */
  /* end INVX1 */
```

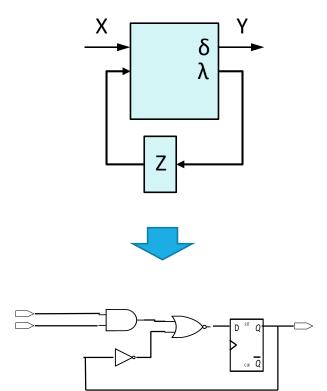
A good cell library features

- •Inverters, buffers, delay cells
- Simple logic functions (e.g. NAND2) and more complex (e.g. AOI, OAI)
- A variety of drive strengths for all cells
- Larger variety of drive strengths for inverters and buffers
- Cells with balanced rise and fall delays (clock gating cells, clock buffers)
- •Flip-flops, latches both positive and negative edge, level sensitive; with optional set/reset pins
- Scan flops, latches
- DFM cells
- •Multiple Process, Voltage and Temperature (PVT) Characterization Corners

CAD problems in standard library design

- Shorten input sequence for SPICE simulation
- Transistor placement automation
- Transistor routing automation
- Design for Manufacturing (DFM) (e.g. metal fill)
- Design rules check efficiency

Logic synthesis



Given: Finite-State Machine $F(X,Y,Z,\lambda,\delta)$ where:

- X: input alphabet
- Y: output alphabet
- Z: set of internal states
- $\lambda : X \times Z \rightarrow Z$ next state function
- δ : X x Z -> Y output function

Produce: circuit C(G,W) where:

- G: set of circuit components (cells)
- W: set of wires connecting G

Logic Synthesis flow

Technology independent optimizations

Logic minimization and restructuring

Cover Boolean network by gates from target cell library

Technology dependent optimizations

Timing optimization; physically driven optimizations

Test logic insertion

CAD problems in logic synthesis

- Minimization of Boolean network
- Optimization of FSM models
 - State minimization, encoding
- Synthesis of sequential multiple-level logic networks: optimization of area, delay, power, testability
- Equivalence verification
- Technology mapping: optimal selection of library cells
- Automatic test pattern generation (ATPG)

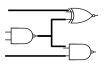
Physical synthesis

•Given:

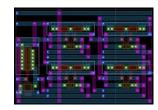
- Gate level netlist
- Physical layout area
- Timing constraints

Produce legal layout:

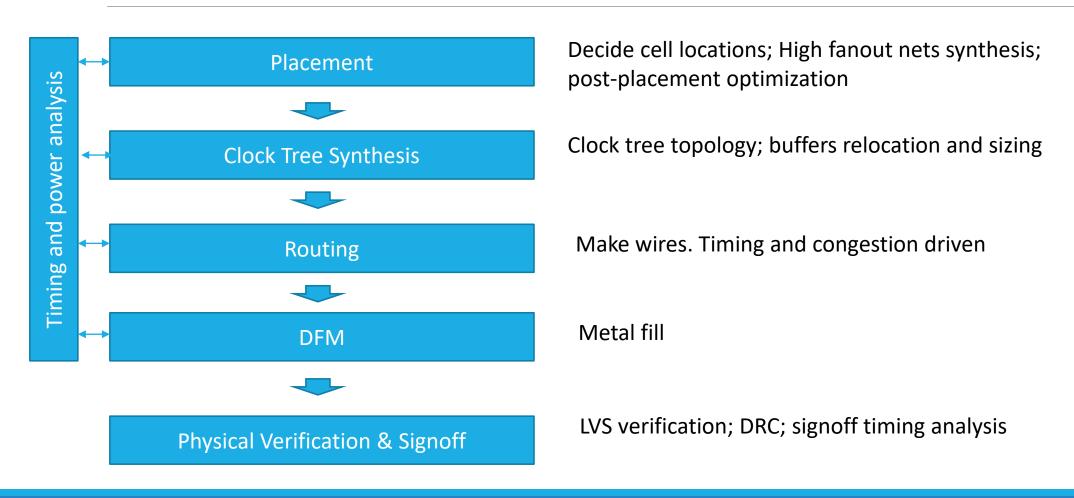
- Assign cell coordinates
- Route wires
- Satisfy design rules and constraints (electrical, DRC, DFM)







Physical synthesis flow



CAD problems in Physical Synthesis

- •Timing analysis: timing graph processing to determine timing violations
- Buffering: high-fanout net synthesis
- Placement: assign netlist nodes location under complex optimization objective and constraints
- Routing: generate correct interconnect layout
- •Gate sizing: select optimal drive strength for circuit cells
- Layout resilience to RTL changes
- Layout geometry rules check and violation detection
- •... and more